

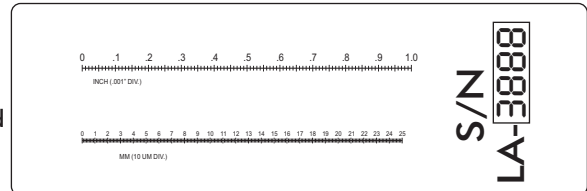
Stage Micrometers

For Stereo and Compound Microscopes, Metallographs,
Video and Automatic Measuring Systems

Stage Micrometers are microscopic rulers used as length standards when calibrating or verifying Image Analyzers, Automatic Micro/Macro Hardness Testers, Video Measuring Systems, Video Prints, or Measuring Reticles.

Dual Use

Suitable for use with low AND high magnification systems. Calibrated at 0.010 mm (10 μ m), 0.10 mm, 0.001 inch, and 0.01 inch increments*. Appears as black lines on a white background in reflected light, and white lines on a dark background in transmitted light. Glass insert in a 1 inch x 3 inch metal slide for durability.



*Reference LECO Stage Micrometer Part Number **863-783-146**

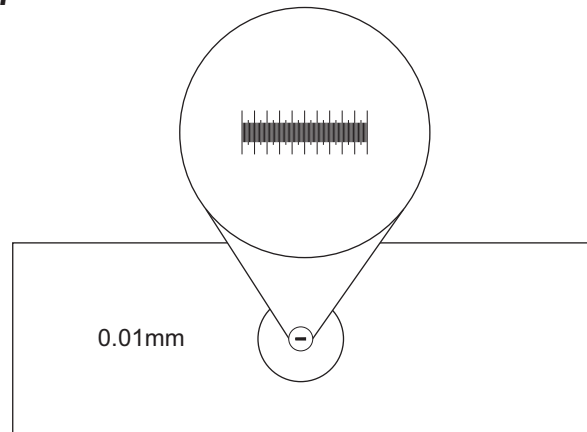
Traceable LECO Stage Micrometer Part Number **863-783-146CERT
(see page 2 for description of reference vs. traceable)

High Magnification Applications

A 1 mm scale optimized for reflected light. Each increment is 0.010 mm (10 μ m). Appears as black lines on a white background. Glass insert in a 1 inch x 3 inch metal slide for durability.

*Reference 1 mm Stage Micrometer Part Number **860-256**

Traceable 1 mm Stage Micrometer Part Number **860-256-110
(see page 2 for description of reference vs. traceable)



860-256 / 860-256-110

Low Magnification (Macro) Applications

English and Metric scales.

English scale is 5 inches long with graduations at each 0.010 inch.

Metric scale is 125 mm long with graduations at each 0.10 mm.

2 inch x 6 inch glass plate.

*Reference Macro Stage Micrometer Part Number **861-249-101**

Traceable Macro Stage Micrometer Part Number **861-375-110



LECO
EMPOWERING RESULTS

Image Analysis Reference Standard 861-249-107

Test Plate	Frame True Size	Description
1	4600 x 3500 μm	CIRCLES with diameters of 2000, 1000, 500, 250 μm ; available for secondary certification on special request; Reference
2	1000 x 800 μm	CIRCLES with diameters of 500, 250, 125, 62.5 μm ; available for secondary certification on special request; Reference
3	1000 x 800 μm	BARS of 200 x 20 μm with 30 degree angles; Reference
4*	2400 x 1620 μm	RANDOM SHAPES: approximately 5, 15, 35, 75, 150, 250, 300, 600, 675 μm high; Reference
5	4000 x 3200 μm	SQUARES of sizes of 100, 40, 20 μm (two sets); Reference
6	2050 x 1650 μm	GRID Pattern with 50 μm holes and walls; Reference
7	4200 x 3400 μm	GRID Pattern with 200 μm holes and walls; Reference
8	10,000 μm long	SCALE (Stage Micrometer) with 10 μm division—10,000 μm long; Traceable

Grain Size/Nodularity Reference Standard

*TEST PLATE #4 has nine randomly generated shapes to stimulate granular features ideally suited for metallurgical calibration where dimensional shapes are to be measured with accuracy (see Figure 1 below).

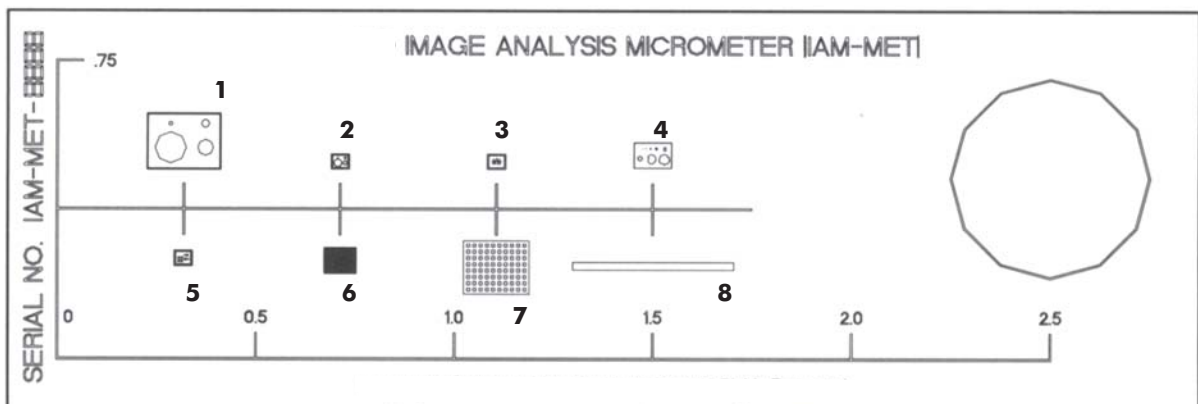


Figure 1

*Reference – No documentation provided. For routine calibration and verification of non-critical measurement systems.

**Traceable – Provided with accredited calibration certificate(s) containing actual measurements for the nominal division markings. Uncertainties are included for each value reported. For routine calibration of critical measurement systems of users subject to audit, or requiring the utmost in accuracy.

Specifications and part numbers may change.
Consult LECO for latest information.

3000 Lakeview Avenue | St. Joseph, MI 49085 | 800-292-6141 | Phone: 269-985-5496
info@leco.com | www.leco.com | ISO-9001:2015 Q-994 | LECO is a registered trademark of LECO Corporation.

LECO Corporation

LECO

EMPOWERING RESULTS